

## **Dual SPDT Switch**

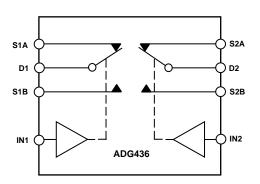
ADG436

#### **FEATURES**

44 V Supply Maximum Ratings  $V_{SS}$  to  $V_{DD}$  Analog Signal Range Low On Resistance (12  $\Omega$  Typ) Low  $\Delta R_{ON}$  (3  $\Omega$  Max) Low  $R_{ON}$  Match (2.5  $\Omega$  Max) Low Power Dissipation Fast Switching Times  $t_{ON} < 175$  ns  $t_{OFF} < 145$  ns Low Leakage Currents (5 nA Max) Low Charge Injection (10 pC) Break-Before-Make Switching Action

APPLICATIONS
Audio and Video Switching
Battery Powered Systems
Test Equipment
Communications Systems

#### FUNCTIONAL BLOCK DIAGRAM



#### **GENERAL DESCRIPTION**

The ADG436 is a monolithic CMOS device comprising two independently selectable SPDT switches. It is designed on an LC<sup>2</sup>MOS process which provides low power dissipation yet gives high switching speed and low on resistance.

The on resistance profile is very flat over the full analog input range ensuring good linearity and low distortion when switching audio signals. High switching speed also makes the part suitable for video signal switching. CMOS construction ensures ultralow power dissipation making the part ideally suited for portable and battery powered instruments.

Each switch conducts equally well in both directions when ON and has an input signal range which extends to the power supplies. In the OFF condition, signal levels up to the supplies are blocked. All switches exhibit break-before-make switching action for use in multiplexer applications. Inherent in the design is low charge injection for minimum transients when switching the digital inputs.

#### PRODUCT HIGHLIGHTS

- Extended Signal Range
   The ADG436 is fabricated on an enhanced LC<sup>2</sup>MOS process, giving an increased signal range which extends to the supply rails.
- 2. Low Power Dissipation
- 3. Low RON
- 4. Single Supply Operation

  For applications where the analog signal is unipolar, the ADG436 can be operated from a single rail power supply.

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# ADG436-SPECIFICATIONS1

# **Dual Supply** $(V_{DD} = +15 \text{ V}, V_{SS} = -15 \text{ V}, GND = 0 \text{ V}, unless otherwise noted})$

Parameter	+25°C	-40°C to +85°C	Units	Test Conditions/ Comments
ANALOG SWITCH				
Analog Signal Range R <sub>ON</sub>	12	$ m V_{SS}$ to $ m V_{DD}$	V Ω typ	$V_D = \pm 10 \text{ V}, I_S = -1 \text{ mA}$
NON	12	25	$\Omega$ max	ν <sub>D</sub> - ± 10 ν, 1 <sub>S</sub> 1 mA
$\Delta R_{ m ON}$	1		Ω typ	$V_D = -5 \text{ V}, 5 \text{ V}, I_S = -10 \text{ mA}$
D. Matak	1	3	Ω max	$V_D = \pm 10 \text{ V}, I_S = -10 \text{ mA}$
R <sub>ON</sub> Match	1	2.5	$\Omega$ typ $\Omega$ max	$V_{\rm D} = \pm 10 \text{ V}, I_{\rm S} = -10 \text{ mA}$
LEAKAGE CURRENTS				$V_{DD} = +16.5 \text{ V}, V_{SS} = -16.5 \text{ V}$
Source OFF Leakage I <sub>S</sub> (OFF)	±0.005		nA typ	$V_D = \pm 15.5 \text{ V}, V_S = \pm 15.5 \text{ V}$
	±0.25	±5	nA max	Test Circuit 2
Channel ON Leakage I <sub>D</sub> , I <sub>S</sub> (ON)	±0.05	1.5	nA typ	$V_S = V_D = \pm 15.5 \text{ V}$ Test Circuit 3
	±0.4	±5	nA max	Test Circuit 3
DIGITAL INPUTS		2.4	***	
Input High Voltage, V <sub>INH</sub> Input Low Voltage, V <sub>INL</sub>		2.4 0.8	V min V max	
Input Corrent		0.6	Villax	
I <sub>INL</sub> or I <sub>INH</sub>		±0.005	μA typ	$V_{IN} = 0 \text{ V or } V_{DD}$
		±0.5	μA max	
DYNAMIC CHARACTERISTICS <sup>2</sup>				
$t_{ON}$	70		ns typ	$R_L = 300 \Omega$ , $C_L = 35 pF$ ;
		125	ns max	$V_S = \pm 10 \text{ V}$ ; Test Circuit 4
$t_{\mathrm{OFF}}$	60	120	ns typ	$R_L = 300 \Omega$ , $C_L = 35 pF$ ;
Break-Before-Make Delay, t <sub>OPEN</sub>	10	120	ns max ns min	$V_S = \pm 10 \text{ V}$ ; Test Circuit 4 $R_L = 300 \Omega$ , $C_L = 35 \text{ pF}$ ;
Break-Beloite-Make Belay, topen	10		115 111111	$V_S = +5 \text{ V}$ ; Test Circuit 5
Charge Injection	10		pC typ	$V_D = 0 \text{ V}, R_D = 0 \Omega, C_L = 10 \text{ nF};$
				Test Circuit 6
OFF Isolation	72		dB typ	$R_L = 75 \Omega$ , $C_L = 5 pF$ , $f = 1 MHz$ ;
Channel-to-Channel Crosstalk	90		dP two	$V_S = 2.3 \text{ V rms}$ , Test Circuit 7 $R_L = 75 \Omega$ , $C_L = 5 \text{ pF}$ , $f = 1 \text{ MHz}$ ;
Chamier-to-Chamier Crosstark	90		dB typ	$V_S = 2.3 \text{ V rms}$ , Test Circuit 8
$C_{S}$ (OFF)	10		pF typ	73 213 7 11115, 1 651 611 611 6
$C_D, C_S(ON)$	30		pF typ	
POWER REQUIREMENTS				
$I_{\mathrm{DD}}$	0.05		mA typ	Digital Inputs = 0 V or 5 V
		0.35	mA max	
$I_{SS}$	0.01	5	μA typ	
$ m V_{DD}/ m V_{SS}$	1	$\pm 3/\pm 20$	μA max V min/V max	$ V_{DD}  =  V_{SS} $
NOTES	1		, 111111 , 1111111	1, 22

Specifications subject to change without notice.

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NOTES

Temperature range is as follows: B Version, -40°C to +85°C.

<sup>&</sup>lt;sup>2</sup>Guaranteed by design, not subject to production test.

## Single Supply $(V_{DD} = +12 \text{ V}, V_{SS} = 0 \text{ V}, \text{ GND} = 0 \text{ V}, \text{ unless otherwise noted})$

Parameter	+25°C	-40°C to +85°C	Units	Test Conditions/ Comments
ANALOG SWITCH Analog Signal Range R <sub>ON</sub> R <sub>ON</sub> Match	20	0 to V <sub>DD</sub> 40 2.5	$V$ $\Omega$ typ $\Omega$ max $\Omega$ max	$V_D = +1 \text{ V}, +10 \text{ V}, I_S = -1 \text{ mA}$
LEAKAGE CURRENTS Source OFF Leakage $I_S$ (OFF) Channel ON Leakage $I_D$ , $I_S$ (ON)	±0.005 ±0.25 ±0.05 ±4	±5 ±5	nA typ nA max nA typ nA max	$V_{DD}$ = +13.2 V $V_{D}$ = 12.2 V/1 V, $V_{S}$ = 1 V/12.2 V Test Circuit 2 $V_{S}$ = $V_{D}$ = 12.2 V/1 V Test Circuit 3
DIGITAL INPUTS Input High Voltage, $V_{INH}$ Input Low Voltage, $V_{INL}$ Input Current $I_{INL}$ or $I_{INH}$		2.4 0.8 ±0.005 ±0.5	V min V max μΑ typ μΑ max	$V_{IN}$ = 0 V or $V_{DD}$
DYNAMIC CHARACTERISTICS <sup>2</sup> t <sub>ON</sub> t <sub>OFF</sub> Break-Before-Make Delay, t <sub>OPEN</sub> Charge Injection  OFF Isolation  Channel-to-Channel Crosstalk  C <sub>S</sub> (OFF) C <sub>D</sub> , C <sub>S</sub> (ON)	100 90 10 10 72 90 10 30	200	ns typ ns max ns typ ns max ns typ pC typ dB typ dB typ pF typ pF typ	$R_{L} = 300 \ \Omega, C_{L} = 35 \ pF;$ $V_{S} = +8 \ V; \ Test \ Circuit \ 4$ $R_{L} = 300 \ \Omega, C_{L} = 35 \ pF;$ $V_{S} = +8 \ V; \ Test \ Circuit \ 4$ $R_{L} = 300 \ \Omega, C_{L} = 35 \ pF;$ $V_{S} = +5 \ V; \ Test \ Circuit \ 5$ $V_{D} = 6 \ V, R_{D} = 0 \ \Omega, C_{L} = 10 \ nF;$ $Test \ Circuit \ 6$ $R_{L} = 75 \ \Omega, C_{L} = 5 \ pF, \ f = 1 \ MHz;$ $V_{S} = 1.15 \ V \ rms; \ Test \ Circuit \ 7$ $R_{L} = 75 \ \Omega, C_{L} = 5 \ pF, \ f = 1 \ MHz;$ $V_{S} = 1.15 \ V \ rms; \ Test \ Circuit \ 8$
POWER REQUIREMENTS $I_{DD}$ $V_{DD}$	0.05	0.35 +3/+30	mA typ mA max V min/V max	V <sub>DD</sub> = +13.5 V Digital Inputs = 0 V or 5 V

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NOTES

1 Temperature range is as follows: B Version, -40°C to +85°C.

<sup>&</sup>lt;sup>2</sup>Guaranteed by design, not subject to production test.

Specifications subject to change without notice.

### **ADG436**

#### ABSOLUTE MAXIMUM RATINGS<sup>1</sup>

SOIC Package	
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$\theta_{JA}$ , Thermal Impedance	77°C/W
Lead Temperature, Soldering	
Vapor Phase (60 sec)	+215°C
Infrared (15 sec)	+220°C

#### NOTES

<sup>1</sup>Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

<sup>2</sup>Overvoltages at IN, S or D will be clamped by internal diodes. Current should be limited to the maximum ratings given.

#### CAUTION\_

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the ADG436 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



#### Table I. Truth Table

ON OFF

#### **ORDERING GUIDE**

Model	Temperature	Package	Package
	Range	Descriptions	Options
ADG436BN	-40°C to +85°C	Plastic DIP	N-16
ADG436BR	-40°C to +85°C	0.15" SOIC	R-16A

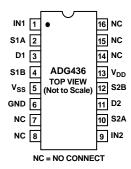
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**ADG436** 

#### **TERMINOLOGY**

	T		1	
$ m V_{DD}$	Most positive power supply potential.	$t_{OFF}$	Delay between applying the digital control	
$V_{SS}$	Most negative power supply potential in dual		input and the output switching off.	
	supplies. In single supply applications, it may	t <sub>OPEN</sub>	Break-before-make delay when switches are	
	be connected to ground.		configured as a multiplexer.	
GND	Ground (0 V) reference.	$V_{INL}$	Maximum input voltage for Logic "0."	
S	Source terminal. May be an input or output.	$V_{INH}$	Minimum input voltage for Logic "1."	
D	Drain terminal. May be an input or output.	$I_{INL}$ ( $I_{INH}$ )	Input current of the digital input.	
IN	Logic control input.	Crosstalk	A measure of unwanted signal that is coupled	
$R_{ON}$	Ohmic resistance between D and S.		through from one channel to another as a result	
$\Delta R_{ON}$	R <sub>ON</sub> variation due to a change in the analog		of parasitic capacitance.	
011	input voltage with a constant load current.	Off Isolation	A measure of unwanted signal coupling	
R <sub>ON</sub> Match	Difference between the $R_{ON}$ of any two channels.		through an "OFF" switch.	
I <sub>S</sub> (OFF)	Source leakage current with the switch "OFF."	Charge Injection	A measure of the glitch impulse transferred	
$I_D$ , $I_S$ (ON)	Channel leakage current with the switch "ON."		from the digital input to the analog output	
$V_D(V_S)$	Analog voltage on terminals D, S.		during switching.	
$C_S$ (OFF)	"OFF" switch source capacitance.	$I_{\mathrm{DD}}$	Positive supply current.	
- , ,	-	$I_{SS}$	Negative supply current.	
$C_D, C_S(ON)$	"ON" switch capacitance.			
$t_{ON}$	Delay between applying the digital control			
	input and the output switching on.			

# PIN CONFIGURATION (DIP/SOIC)



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## **ADG436—Typical Performance Characteristics**

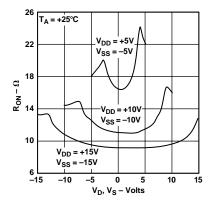


Figure 1.  $R_{ON}$  as a Function of  $V_D$  ( $V_S$ ): Dual Supply

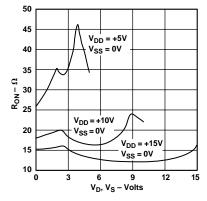


Figure 2.  $R_{ON}$  as a Function of  $V_D$  ( $V_S$ ): Single Power Supply

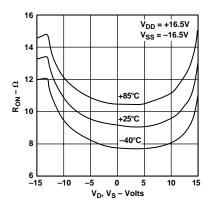


Figure 3.  $R_{ON}$  as a Function of  $V_D$  ( $V_S$ ) for Different Temperatures: Dual Supply

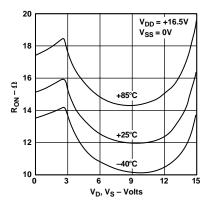


Figure 4.  $R_{ON}$  as a Function of  $V_D$  ( $V_S$ ) for Different Temperatures: Single Supply

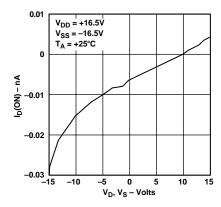


Figure 5.  $I_D$  (ON) Leakage Current as a Function of  $V_D$  ( $V_S$ ): Dual Supply

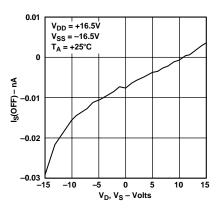


Figure 6.  $I_S$  (OFF) Leakage Current as a Function of  $V_D$  ( $V_S$ ): Dual Supply

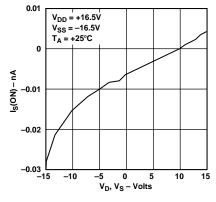


Figure 7.  $I_S$  (ON) Leakage Current as a Function of  $V_D$  ( $V_S$ ): Dual Supply

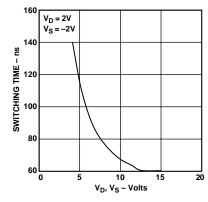


Figure 8. Switching Time as a Function of  $V_D$  ( $V_S$ ): Dual Supply

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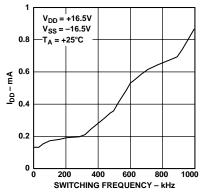
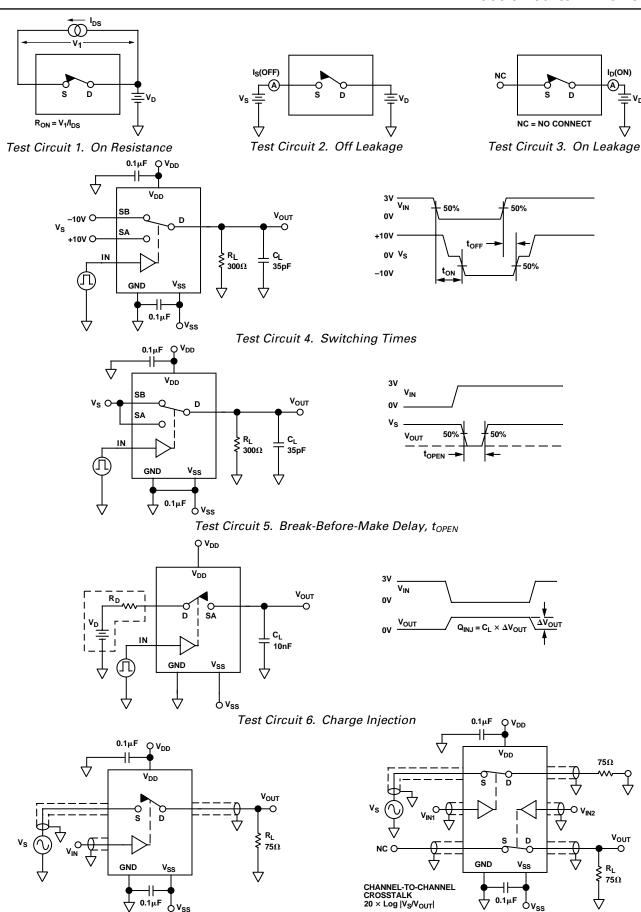


Figure 9.  $I_{DD}$  as a Function of Switching Frequency: Dual Supply

## Test Circuits—ADG436

Test Circuit 8. Channel-to-Channel Crosstalk



Test Circuit 7. Off Isolation
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### **ADG436**

#### APPLICATIONS INFORMATION

#### **ADG436 Supply Voltages**

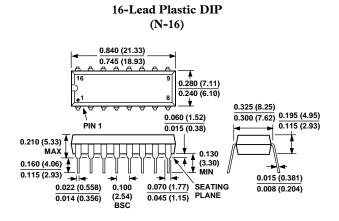
The ADG436 can operate from a dual or single supply.  $V_{SS}$  should be connected to GND when operating with a single supply. When using a dual supply, the ADG436 can also operate with unbalanced supplies, for example  $V_{DD}$  = 20 V and  $V_{SS}$  = –5 V. The only restrictions are that  $V_{DD}$  to GND must not exceed 30 V,  $V_{SS}$  to GND must not drop below –30 V and  $V_{DD}$  to  $V_{SS}$  must not exceed +44 V. It is important to remember that the ADG436 supply voltage directly affects the input signal range, the switch ON resistance and the switching times of the part. The effects of the power supplies on these characteristics can be clearly seen from the characteristic curves in this data sheet.

#### **Power-Supply Sequencing**

When using CMOS devices, care must be taken to ensure correct power-supply sequencing. Incorrect power-supply sequencing can result in the device being subjected to stresses beyond those maximum ratings listed in the data sheet. Always sequence  $V_{\rm DD}$  on first followed by  $V_{\rm SS}$  and the logic signals. An external signal can then be safely presented to the source or drain of the switch.

#### **OUTLINE DIMENSIONS**

Dimensions are shown in inches and (mm).



#### (R-16A)0.3937 (10.00) 0.3859 (9.80) 0.1574 (4.00) 0.2550 (6.20) 0.1497 (5.80) 0.2284 (5.80) 0.0196 (0.50) x 45° 0.0688 (1.75) 0.0098 (0.25) 0.0532 (1.35) 0.0099 (0.25) 0.0040 (0.10) 0.0500 0.0192 (0.49) SEATING 0.0099 (0.25) 0.0500 (1.27) 0.0138 (0.35) PLANE 0.0075 (0.19) 0.0160 (0.41)

16-Lead Narrow Body SOIC